

<b>Notice of References Cited</b>	Application/Control No. 09/934,879	Applicant(s)/Patent Under Reexamination BEAN ET AL.	
	Examiner Ba Huynh	Art Unit 2173	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,574,416	06-2003	Posa et al.	386/69
	B	US-6,650,826	11-2003	Hatta, Masashi	386/52
	C	US-2002/0175917	11-2002	Chakravarty et al.	345/473
	D	US-6,404,978	06-2002	Abe, Keiko	386/55
	E	US-6,081,264	06-2000	Rosen et al.	345/723
	F	US-5,760,767	06-1998	Shore et al.	345/723
	G	US-5,682,326	10-1997	Klingler et al.	715/500.1
	H	US-6,597,375	07-2003	Yawitz, Mitchell A.	345/723
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Te